A Fast and Ultrasensitive Electrometer Operating at the Single-Photon Level

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We demonstrate fast and ultrasensitive charge detection with a cavity-embedded Cooper pair transistor via dispersive readout of its Josephson inductance. We report a minimum charge sensitivity of $14 \, \mu e/\sqrt{\text{Hz}}$ with a detection bandwidth on the order of 1 MHz using 16 attowatts of power, corresponding to the single-photon level of the cavity. In addition, our measured sensitivities are within a factor of 5 of the quantum limit for this device. This is the first ultrasensitive electrometer reported to operate at the single-photon level and its sensitivity is comparable to rf-SETs, which typically require picowatts of power. Our results support the feasibility of using this device to mediate an optomechanical interaction that reaches the single-photon strong coupling regime.

Fast and ultrasensitive electrometers have been instrumental to the advancement of basic science. They have been used to detect in real time the tunneling of electrons in a quantum dot [1], determine the tunneling rates of quasiparticles in superconducting devices [2], and study the properties of Majorana zero modes in nanowires [3]. In addition, the rapid detection of single electrons is crucial for the readout of quantum-dot-based qubits [4], for which operating at lower photon numbers reduces measurement backaction [5]. In this same vein, ultrasensitive electrometers are at the heart of many schemes for sensing the displacement of charged mechanical resonators [6,8], as well as for coherently coupling mechanical resonators to microwave cavities [9,11]. To observe and take advantage of quantum effects in such hybrid systems it is often essential that their coupling be strong at the single-photon level, a regime that has been achieved for quantum dots [12,13] but not yet for mechanical resonators despite significant effort [14,17]. Reaching the single-photon strong optomechanical coupling regime, where a single cavity photon causes sufficient radiation pressure to displace the mechanical resonator by more than its zero-point uncertainty, would enable the generation of nonclassical states of both light and motion [18,19], as well as provide a rich platform for studying the quantum-to-classical transition and other fundamental physics [20].

Electrometers based on the single electron transistor (SET) are among the fastest and most sensitive reported in the literature to date. Radio-frequency single electron transistors (rf-SETs) are the best known of these devices, having achieved sensitivities below $1 \, \mu e/\sqrt{\text{Hz}}$ [21] and bandwidths greater than 100 MHz [22]. The rf-SET functions by encoding the charge gating the SET in the power dissipated by the SET, which is embedded in a tank circuit to enable radio-frequency readout of this dissipation. This dissipative detection typically requires picowatts of power, corresponding to hundreds of thousands of photons in the tank circuit, which renders the rf-SET unsuitable for some of the aforementioned applications and makes it impossible to integrate the rf-SET with modern near-quantum-limited parametric amplifiers [23,27] (which typically saturate well below the picowatt scale).

Dispersive electrometers based on the SET have also been developed, which encode the gate charge in the resonant frequency of a tank circuit. Such electrometers have been operated using femtowatts of power [2,26], corresponding to tens or hundreds of photons, and have achieved charge sensitivities as low as $30 \, \mu e/\sqrt{\text{Hz}}$ [27]. More recently, dispersive gate-based sensors have been developed [28] that have surpassed the performance of SET-based electrometers. These devices have achieved sensitivities as low as $0.25 \, \mu e/\sqrt{\text{Hz}}$ with detection bandwidths approaching 1 MHz while using only 100 attowatts of power, corresponding to hundreds of photons [29].

In this letter we demonstrate ultrasensitive dispersive charge detection with a cavity-embedded Cooper pair transistor (cCPT) [30,31]. Using 16 attowatts of power, corresponding to the single-photon level of the cavity, we measure a minimum charge sensitivity of $14 \, \mu e/\sqrt{\text{Hz}}$. Relative to theory, we find that the cCPT operates within a factor of 5 of its quantum-limited sensitivity, this discrepancy being due to the presence of frequency fluctuations comparable to the cavity linewidth, the inherent nonlinearity of the device, and the noise of our amplifier chain. Another major limitation of the present device is quasiparticle poisoning [32], which prevents us from studying the cCPT at its theoretically-optimal operating point. Based on these results we expect an optimized sample could realistically achieve a sensitivity as low as $0.4 \, \mu e/\sqrt{\text{Hz}}$, rivaling that of the best gate-based sensor [29]. This is the first ultrasensitive electrometer reported to operate at the single-photon level; for this reason, the cCPT has been proposed as a platform for reaching the single-photon strong coupling regime of optomechanics [9]. Our results support the feasibility of this proposal and represent an important step toward its realization.

We study the same device characterized experimentally in Ref. [30]. The cCPT, depicted schematically in Fig. 1(a), has two components: a quarter-wavelength $(\lambda/4)$ coplanar waveguide cavity and a Cooper pair transistor (CPT). The CPT consists of two Josephson junctions (JJ$s$) with an island between them that can be gated via the capacitance $C_g$. The CPT is connected between the voltage antinode of the cavity and the ground.
plane, such that the two form a SQUID loop. Embedded in this way, the CPT behaves as a nonlinear Josephson inductance $L_J$ in parallel with the cavity that can be tuned by both the number of electrons $n_g$ gating the island and the flux $\Phi_{\text{ext}}$ threading the SQUID loop. The gate charge $n_g$ is thus encoded in the resonant frequency $\omega_0$ of the cavity, which can then be detected via microwave reflectometry. The theoretical charge sensitivity of the cCPT in this mode of operation is derived from first principles in Ref. 31. This device can be operated at much lower powers than comparable SET-based dispersive electrometers 2 30 27 for two key reasons. First, we use a distributed superconducting microwave cavity rather than a lumped-element LC circuit, yielding much lower dissipation. Second, we can tune the CPT band structure via the external flux $\Phi_{\text{ext}}$, which provides us greater flexibility in biasing the device to an optimally-sensitive point.

To measure the charge sensitivity of the cCPT we drive the cavity with a resonant carrier signal while modulating the gate about a dc bias point $n_g$ such that $n_g(t) = n_g + \sqrt{2}(q_{\text{rms}}/e)\cos(\omega_0 t)$, which in turn modulates the resonant frequency such that $\omega_0(t) = \omega_0 + \sqrt{2}(\partial \omega_0/\partial n_g)(q_{\text{rms}}/e)\cos(\omega_0 t)$. As a result, the reflected carrier signal is phase-modulated leading to output power $P_{\text{out}}$ proportional to $q_{\text{rms}}^2$ at the sideband frequencies $\omega_0 \pm \omega_g$. Since the charge sensitivity $\delta q$ is defined as the rms charge amplitude per $\sqrt{Hz}$ that yields a signal to noise ratio of unity, it can be expressed as

$$\delta q = q_{\text{rms}} \sqrt{\frac{S_{\text{noise}}}{P_{\text{out}}(\omega_0 + \omega_g) + P_{\text{out}}(\omega_0 - \omega_g)}}.$$  \hspace{1cm} (1)$$

where $S_{\text{noise}}$ is the power spectral density of the noise floor near the sideband frequencies. Here we consider the total power at the two sidebands to be the signal of interest, since it is possible to combine them via homodyne mixing 21. Thus, given the rms charge modulation amplitude $q_{\text{rms}}$, we can use a spectrum analyzer with resolution bandwidth $B$ to measure both the output sideband power and the noise floor $P_{\text{noise}} = B \times S_{\text{noise}}$, from which we can extract the charge sensitivity $\delta q$. Assuming symmetric sidebands, Eq. 1 can be rewritten in the more familiar form $\delta q = q_{\text{rms}}/\sqrt{2B \times 100\%}$, where SNR is the single-sideband signal to noise ratio expressed in decibels 21, 34. In practice, however, we observe asymmetric sidebands and therefore use Eq. 1 to extract the charge sensitivity from our measurements. We do not yet understand the origin of this asymmetry, which can be several dB, but we find it is correlated with the detuning of the carrier from resonance such that the right sideband tends to be larger than the left for negative detuning and vice versa for positive detuning.

Theoretically, $P_{\text{out}}(\omega_0 \pm \omega_g)$ can be expressed as

$$P_{\text{out}}(\omega_0 \pm \omega_g) = \frac{2\kappa_{\text{ext}}^2}{\kappa_{\text{tot}}^2(\omega_g^2 + \kappa_{\text{ext}}^2/4)} \frac{q_{\text{rms}}}{e} \frac{\partial \omega_0}{\partial n_g} \frac{P_{\text{in}}}{\text{SNR}}.$$  \hspace{1cm} (2)$$

where $\kappa_{\text{ext}}$ and $\kappa_{\text{tot}}$ are the external and total damping rates of the cavity, respectively, and $P_{\text{in}}$ is the input carrier power at the plane of the sample. The theoretical charge sensitivity can therefore be expressed as

$$\delta q = \frac{\kappa_{\text{tot}}}{2\kappa_{\text{ext}}} \sqrt{\frac{S_{\text{noise}}}{P_{\text{in}}}} \left(\omega_g^2 + \frac{\kappa_{\text{ext}}^2}{4}\right) \frac{1}{\left|\frac{\partial \omega_0}{\partial n_g}\right| \text{SNR}}.$$  \hspace{1cm} (3)$$

To evaluate this expression we use the sample-referred $S_{\text{noise}}$ and $P_{\text{in}}$ (discussed below), as well as the values of $\kappa_{\text{ext}}$, $\kappa_{\text{tot}}$, and $\omega_0(n_g, \Phi_{\text{ext}})$ determined from a detailed characterization of the device 30. The damping rates are approximately $\kappa_{\text{ext}}/2\pi \approx 1.2$ MHz and $\kappa_{\text{tot}}/2\pi \approx 1.4$ MHz, though these depend on $\omega_0(n_g, \Phi_{\text{ext}})$ and can vary by 10%–20%. The corresponding quantum-limited sensitivity of the device is obtained by evaluating Eq. 3 at the quantum limit of system noise for our measurement scheme, $S_{\text{noise}}^{QL} = h\omega_0$, as discussed below.
It is important to note that both Eqs. $\frac{1}{1}$ and $\frac{3}{3}$ are only valid when $q_{\text{rms}}/ε < \omega_g/\left(\partial \omega_0/\partial n_g\right)$, which ensures that the amplitude of the resulting frequency modulation is small compared to $\omega_g$, and that $P_{\text{out}}(\omega_0 \pm \omega_g)$ is proportional to $q_{\text{rms}}^2$. In all of our measurements we use sufficiently small $q_{\text{rms}}$ to satisfy this constraint. Furthermore, Eq. $\frac{3}{3}$ is most accurate in the linear response regime for which $n < \kappa_{\text{tot}}/|K|$, where $n = 4\kappa_{\text{ext}}P_{\text{in}}/\hbar\omega_0\kappa_{\text{tot}}^2$ is the average number of intracavity photons and $K$ is the Kerr nonlinearity of the cCPT $\frac{30}{30}$. Experimentally, we find that for $n < \kappa_{\text{tot}}/|K|$ the output sideband power grows linearly with $P_{\text{in}}$ as expected from Eq. $\frac{2}{2}$, but as $n$ approaches $\kappa_{\text{tot}}/|K|$ this trend becomes sub-linear. Near this threshold, $P_{\text{out}}(\omega_0 \pm \omega_g)$ begins to decrease with increasing $P_{\text{in}}$. We therefore use sufficiently small input powers such that $n \lesssim 1$ in all of our measurements, since $\kappa_{\text{tot}}/|K| > 1.7$ for all values of $n_g$ and $\Phi_{\text{ext}}$. $\frac{30}{30}$.

The detection bandwidth of the present device, which determines the maximum rate at which the cavity can respond to changes in the gate charge $n_g$, is set by $\kappa_{\text{tot}}$ and is on the order of 1 MHz. This can be improved by using a larger coupling capacitance $C_c$, thereby increasing $\kappa_{\text{ext}}$, but this improved bandwidth also affects the charge sensitivity. Restricting ourselves to single-photon-level operation and assuming negligible internal loss such that $\kappa_{\text{tot}} \approx \kappa_{\text{ext}}$, Eq. $\frac{3}{3}$ becomes

$$\delta q = \frac{1}{2} \sqrt{\kappa_{\text{tot}}} \frac{S_{\text{noise}}(\omega)}{\hbar\omega_0} \left| \frac{\partial \omega_0}{\partial n_g} \right|^{-1} e$$

for $\omega_g \ll \kappa_{\text{tot}}$. Thus, the bandwidth can be improved at the price of sensitivity, and vice versa.

The cCPT is housed in a dilution refrigerator with a base temperature of $T \lesssim 30$ mK and measured using the circuitry depicted schematically in Fig. $\frac{1}{1}$b), which is nearly identical to that used in Ref. $\frac{30}{30}$. The one difference here is that we use a near-quantum-limited TWPA $\frac{23}{23}$ as a first-stage amplifier, followed by a cryogenic HEMT amplifier and room temperature amplifier. We use the techniques described in Ref. $\frac{30}{30}$ to refer all input and output powers, as well as the system noise $S_{\text{noise}}(\omega)$, to the plane of the sample. The measured system noise, shown in Fig. $\frac{1}{1}$c), is due to the half-photon of vacuum noise $S_{\text{vac}} = \hbar\omega/2$ in the input/output transmission line $\frac{35}{35}$ and the added noise of our amplifier chain $S_{\text{amp}}$, such that $S_{\text{noise}} = S_{\text{vac}} + S_{\text{amp}}$. For all of the charge sensitivity measurements we report, the noise floor near the sideband frequencies is dominated by this system noise, which is why we use the same notation for these two quantities. At sufficiently low gate modulation frequencies, however, the noise floor is dominated by $1/f$ charge noise $\frac{36}{36}$. In our case this regime is below about 1 kHz $\frac{30}{30}$. We determine the noise added by the TWPA and HEMT independently by measuring the gain of the amplifier chain and total system noise twice: once with the TWPA pump on and once with it off. Over the working range of resonant frequencies of the cCPT (between 5.68 GHz and 5.82 GHz), the TWPA contributes 1.2 photons of noise (50% of total) while the HEMT contributes 0.7 photons (30% of total) on average. The room temperature amplifier contributes negligibly to $S_{\text{noise}}$. The quantum limit of noise in this system is one photon, such that $S_{\text{noise}}^{\text{GL}} = \hbar\omega$, since phase-insensitive amplifiers must add at least a half-photon of noise $\frac{37}{37}$. Thus, our average system noise is only a factor of 2.4 greater than the quantum limit for this measurement scheme, such that the theoretical sensitivity (Eq. $\frac{3}{3}$) is only a factor of $\sqrt{2.4}$ greater than the quantum-limited sensitivity.

In order to compare the cCPT’s charge sensitivity with its theoretical performance, given by Eq. $\frac{3}{3}$, we first measure $\delta q$ as a function of both the gate charge $n_g$ and external flux $\Phi_{\text{ext}}$. Although we can access a full period of $\Phi_{\text{ext}}$ (from 0 to the magnetic flux quantum $\Phi_0$), we can only access the gate range $0.65 < n_g < 0.65$ due to quasiparticle poisoning $\frac{39}{39}$. We perform this measurement using an input power $P_{\text{in}} = -141$ dBm $\approx 8$ aW and gate modulation amplitude $q_{\text{rms}} = 10^{-3} e$. Ideally we would set $\omega_g$ to be significantly less than $\kappa_{\text{tot}}/2 \approx 2 \pi \times 700$ kHz to minimize Eq. $\frac{3}{3}$, but in our experiments we observe cross-talk between our gate and flux lines at frequencies below about 650 kHz. We therefore use $\omega_g/2\pi = 500$ kHz, such that the gate modulation does not also induce a flux modulation. To measure the reflected power and noise floor at $\omega_0 \pm \omega_g$, we use a resolution bandwidth $B = 1$ Hz.

![Figure 2](image-url)
TABLE I. Comparison of the cCPT with a representative set of fast and ultrasensitive electrometers. Asterisks indicate dispersive electrometers.

<table>
<thead>
<tr>
<th>Electrometer</th>
<th>$\delta q$ (µe/√Hz)</th>
<th>$P_{in}$ (aW)</th>
<th># photons</th>
</tr>
</thead>
<tbody>
<tr>
<td>cCPT*</td>
<td>14</td>
<td>16</td>
<td>1</td>
</tr>
<tr>
<td>Best gate sensor</td>
<td>0.25</td>
<td>100</td>
<td>190</td>
</tr>
<tr>
<td></td>
<td>0.9</td>
<td>$6 \times 10^6$</td>
<td>2 $\times 10^8$</td>
</tr>
<tr>
<td>Best rf-SET</td>
<td>2.3</td>
<td>$3 \times 10^8$</td>
<td>2 $\times 10^6$</td>
</tr>
<tr>
<td>L-SET[27]*</td>
<td>30</td>
<td>$1 \times 10^4$</td>
<td>70</td>
</tr>
<tr>
<td>Naaman et al.[24]*</td>
<td>52</td>
<td>$2 \times 10^3$</td>
<td>150</td>
</tr>
<tr>
<td>Bell et al.[10]*</td>
<td>70</td>
<td>$3 \times 10^7$</td>
<td>2 $\times 10^6$</td>
</tr>
<tr>
<td>rf-QPC[11]</td>
<td>200</td>
<td>$1 \times 10^9$</td>
<td>7 $\times 10^7$</td>
</tr>
</tbody>
</table>

The results of this measurement are shown in Fig. 2(a). We find that the variation of $\delta q$ with $n_g$ and $\Phi_{ext}$ is in good agreement with our theory, but our measured sensitivities are about 3 times worse than theory. We attribute this discrepancy to two factors. First and foremost, the resonant frequency fluctuates due to $1/f$ charge and flux noise [30, 35] over the course of each measurement, which means our carrier is not always on resonance. On average, this reduces the output sideband power yielding worse charge sensitivity than expected. Second, we used a sufficiently high input power that $P_{out}(\omega_0 \pm \omega_g)$ scales sublinearly with $P_{in}$ due to the Kerr nonlinearity. Although this improves the sensitivity overall and was necessary to resolve the sidebands over a large area of the gate/flux parameter space, it causes the measured sensitivity to diverge from theory since the latter assumes proportionality between $P_{in}$ and $P_{out}(\omega_0 \pm \omega_g)$.

Finally, accounting for the fact that $S_{\text{noise}}/S_{\text{QL}} \approx 2.4$, the factor of 3 discrepancy between theory and experiment means our measured sensitivities are within a factor of 5 of the quantum limit. In this measurement we find a minimum charge sensitivity of 24 µe/√Hz at $(n_g, \Phi_{ext}) = (0.63, 0.0)$, whereas our predicted theoretical and quantum-limited sensitivities at this point are 9 µe/√Hz and 6 µe/√Hz, respectively.

In order to optimize $\delta q$ we narrow our search to the gate range $0.6 \leq |n_g| \leq 0.65$ and the flux points $\Phi_{ext} = 0, \Phi_0/2$. At these flux points the resonant frequency of the cCPT is insensitive to flux, so we can reduce our gate modulation frequency to $\omega_g/2\pi \approx 350$ kHz without the gate/flux cross-talk interfering with our results. To maintain a small frequency modulation amplitude relative to $\omega_g$, we also reduce $q_{\text{rms}}$ to $5 \times 10^{-4}$. For this measurement we use a repetition bandwidth $B = 10$ Hz.

We find a minimum charge sensitivity of 14 µe/√Hz at $(n_g, \Phi_{ext}) = (0.625, 0.0)$ using an input power $P_{in} = -138$ dBm $\approx 16$ aW. Under these conditions our predicted theoretical and quantum-limited sensitivities are 5 µe/√Hz and 3 µe/√Hz, respectively. The spectrum analyzer trace of this optimal measurement is shown in Fig. 2(b). At this bias point the resonant frequency is $\omega_0/2\pi = 5.806$ GHz, the external damping is $\kappa_{ext}/2\pi = 1.24$ MHz, and the total damping is $\kappa_{tot}/2\pi = 1.62$ MHz, such that the number of intracavity photons is $n = 4\kappa_{ext}P_{in}/\hbar\omega_0\kappa_{tot}^2 \approx 1$. This is the first ultrasensitive electrometer reported to operate at the single-photon level. Furthermore, its sensitivity is rivaled only by gate-based sensors [29, 36] and carbon nanotube-based rf-SETs [39]. In Table I we compare the performance of the cCPT to a representative set of fast (detection bandwidth $\gtrsim 1$ MHz) and ultrasensitive ($\delta q < 10^{-3}e/\sqrt{\text{Hz}}$) electrometers. Clearly, the cCPT is unparalleled in its ability to operate at low powers and photon numbers. As discussed earlier, this makes it ideal for mediating an optomechanical interaction that reaches the single-photon strong coupling regime [9].

There remains significant room for improving the sensitivity of the cCPT, with two distinct approaches for doing so. The most promising approach is to reduce quasiparticle poisoning (QP) [32], which prevents us from operating at gate biases above $|n_g| \approx 0.65$ [30]. If we were able to operate the present device at $(n_g, \Phi_{ext}) = (0.9, \Phi_0/2)$ we would expect to attain a charge sensitivity of $\delta q \approx 0.4$ µe/√Hz, assuming the same factor of 3 discrepancy with theory as we observe experimentally. The present device was designed with a 9 nm thick CPT island [30] to suppress QP [42], but other fabrication techniques could be employed to reduce it further. These include oxygen doping the CPT island [22] and embedding quasiparticle traps near the CPT [43].

The other approach is to mitigate the discrepancy between our measured sensitivities and the quantum limit of sensitivity for the cCPT. One such improvement would be to use a truly quantum-limited amplifier, which would improve our sensitivities by a factor of $\sqrt{S_{\text{noise}}/\hbar\omega} \approx 2.4$. Another such improvement would be to stabilize the resonant frequency using a Pound-locking loop [44], thereby reducing the scale of frequency fluctuations induced by $1/f$ noise, which we expect would substantially improve the sensitivity of the cCPT.

Finally, it may be possible to improve the sensitivity of the cCPT by employing more sophisticated charge detection schemes. For example, the cCPT can be driven to its bifurcation point, set by the Kerr nonlinearity, where the slope of the cavity response with respect to detuning diverges. At this point the charge modulation would induce a stronger modulation of the reflected signal and thus improved sensitivity [45, 46]. It is difficult to operate at this point, however, since frequency fluctuations blur the sharp cavity response. Another possibility is to incorporate parametric pumping of the flux at $2\omega_0$ to improve sensitivity. If biased near the threshold of parametric oscillation, small changes in the gate charge would yield huge changes in the oscillation amplitude. Such a scheme has previously been used to achieve single-shot readout of a superconducting qubit [47].
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